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# INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Sheet 1 of 1

## Complete if Known

Application Number	Not Yet Assigned
Confirmation Number	Not Yet Assigned
Filing Date	July 29, 2003
First Named Inventor	Ulrich WEGMANN
An Unit	Not Yet Assigned
Examiner Name	Not Yet Assigned
Attorney Docket Number	Q76579

## U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. <sup>1</sup>	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code <sup>2</sup> (if known)		
	SAT	US 5 965 874		10/12/1999	THE FURUKAWA ELECTRIC CO., LTD. Aso, et al.
	↑	US 5 396 329		3/7/1995	BRITISH AEROSPACE PLC Kalawsky
	↑	US 5 298 972		3/29/1994	HEWLETT-PACKARD COMPANY Heffner
	↑	US 5 227 623		7/13/1993	HEWLETT-PACKARD COMPANY Heffner
	↑	US 5 166 752		11/24/1992	RUDOLPH RESEARCH CORPORATION Spanier, et al.
	↑	US 6 204 924		3/20/2001	EXFO ELECTRO-OPTICAL ENGINEERING INC. Cyr
	↑	US 6 312 373	B1	11/6/2001	NIKON CORPORATION J. Chihara
	↑	US 6 344 898	B1	2/5/2002	NIKON CORPORATION G. Emma, et al.
	SAT	US 2002/0024673	A1	2/28/2002	CHIDANE OUCHI

## FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Translation <sup>4</sup>
		Country Code <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>2</sup> (if known)			
	SAT	DE	101 09 929	A1	11/22/2001	CARL ZEISS	
	↑	EP	0 439 127	A2	7/31/1991	HEWLETT-PACKARD COMPANY	
	↑	EP	0 396 409	A2	11/7/1990	THERMA-WAVE INC.	
	↑	JP	11-142291	A	5/28/1999	NIKON CORPORATION	Abstract
	↓	WO	02/42728	A1	5/30/2002	NIKON CORPORATION	Abstract
	SAT	WO	03/028073	A1	4/3/2003	NIKON CORPORATION	Claims

## NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation <sup>4</sup>
SAT		"OPTICAL SHOP TESTING", EDITED BY: DANIEL MALACARA, JOHN WILEY & SONS, INC., SECOND EDITION, PAGES 112-113, 1992, USA.	
SAT		MICHAEL I. SHRIBAK ET AL. "RETURN-PATH POLARIMETER FOR TWO DIMENSIONAL BIREFRINGENCE DISTRIBUTION MEASUREMENT", JULY 1999, SPIE, PAGES 144-145 AND 148-149, VOLUME 3654, DENVER COLORADO	
SAT		S. BEREZHNA, ET AL. "ACCURACY OF WHOLE-FIELD MAPPING BY JONES MATRIX FOURIER PHOTOPOLARIMETER", 2000, PROCEEDINGS OF SPIE, PAGES 81-89, VOLUME 4148	

Examiner Signature

S.A. Tuvaca

Date Considered

2-13-06

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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